# **Power MOSFET**

# 30 V, 12 A, Single N-Channel, SO-8

#### **Features**

- Low R<sub>DS(on)</sub>
- Low Gate Charge
- Standard SO-8 Single Package
- Pb-Free Package is Available

## **Applications**

- Notebooks, Graphics Cards
- Synchronous Rectification
- High Side Switch
- DC-DC Converters

## **MAXIMUM RATINGS** (T<sub>J</sub> = 25°C unless otherwise stated)

Parameter			Symbol	Value	Unit
Drain-to-Source Voltage			$V_{DSS}$	30	V
Gate-to-Source Voltage	Gate-to-Source Voltage			±20	V
Continuous Drain	Steady	T <sub>A</sub> = 25°C	I <sub>D</sub>	10	Α
Current (Note 1)	State	T <sub>A</sub> = 85°C		7.2	
	t ≤ 10 s	T <sub>A</sub> = 25°C		12	
Power Dissipation (Note 1)	Steady State	T <sub>A</sub> = 25°C	P <sub>D</sub>	1.52	W
	t ≤ 10 s			2.3	
Continuous Drain	Steady	T <sub>A</sub> = 25°C	I <sub>D</sub>	7.4	Α
Current (Note 2)	State	T <sub>A</sub> = 85°C		5.3	
Power Dissipation (Note 2)		T <sub>A</sub> = 25°C	P <sub>D</sub>	0.85	W
Pulsed Drain Current	t <sub>p</sub> = 10 μs		I <sub>DM</sub>	36	Α
Operating Junction and Storage Temperature			T <sub>J</sub> , T <sub>stg</sub>	-55 to 150	°C
Source Current (Body Diode)			IS	3.0	Α
Single Pulse Drain-to-Source Avalanche Energy ( $V_{DD}$ = 25 V, $V_{GS}$ = 10 V, Peak I <sub>L</sub> = 7.5 A, L = 10 mH, $R_G$ = 25 $\Omega$ )		E <sub>AS</sub>	210	mJ	
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)		TL	260	°C	

## THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Ambient - Steady State (Note 1)	$R_{\theta JA}$	82	°C/W
Junction–to–Ambient – $t \le 10 \text{ s (Note 1)}$	$R_{\theta JA}$	55	
Junction-to-Ambient - Steady State (Note 2)	$R_{\theta JA}$	147	

Maximum ratings are those values beyond which device damage can occur. Maximum ratings applied to the device are individual stress limit values (not normal operating conditions) and are not valid simultaneously. If these limits are exceeded, device functional operation is not implied, damage may occur and reliability may be affected.

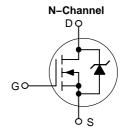
- 1. Surface mounted on FR4 board using 1 in sq pad size (Cu area = 1.127 in sq [1 oz] including traces).
- 2. Surface mounted on FR4 board using the minimum recommended pad size.



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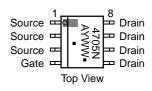
V <sub>(BR)DSS</sub>	R <sub>DS(ON)</sub> TYP	I <sub>D</sub> MAX (Note 1)
30 V	$8.0~\text{m}\Omega$ @ $10~\text{V}$	12 A
30 V	10.5 m $\Omega$ @ 4.5 V	12.4



## MARKING DIAGRAM/ PIN ASSIGNMENT



SO-8 CASE 751 STYLE 12



4705N = Device Code A = Assembly Location

Y = Year WW = Work Week ■ = Pb-Free Package

(Note: Microdot may be in either location)

## **ORDERING INFORMATION**

Device	Package	Shipping <sup>†</sup>
NTMS4705NR2	SO-8	2500/Tape & Reel
NTMS4705NR2G	SO-8 (Pb-Free)	2500/Tape & Reel

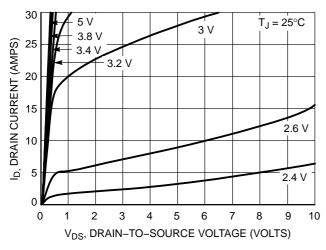
†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

# **ELECTRICAL CHARACTERISTICS** ( $T_J = 25^{\circ}C$ unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS	•		•				
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		30			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V <sub>(BR)DSS</sub> /T <sub>J</sub>				15		mV/°C
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	Vcc = 0 V. Vcc =	T <sub>J</sub> = 25°C			1.0	μΑ
		$V_{GS} = 0 \text{ V, } V_{DS} = 24 \text{ V}$	T <sub>J</sub> = 125°C			50	1
Gate-to-Source Leakage Current	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$				±100	nA
ON CHARACTERISTICS (Note 3)	•		•		•	•	
Gate Threshold Voltage	V <sub>GS(TH)</sub>	$V_{GS} = V_{DS}, I_{D} = 250 \mu A$		1.0		2.5	V
Negative Threshold Temperature Coefficient	V <sub>GS(TH)</sub> /T <sub>J</sub>				5.0		mV/°C
Drain-to-Source On Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 12 A			8.0	10	mΩ
		V <sub>GS</sub> = 4.5 V, I <sub>D</sub> = 10 A			10.5	14	1
Forward Transconductance	9FS	V <sub>DS</sub> = 15 V, I <sub>D</sub>	= 10 A		19		S
CHARGES, CAPACITANCES AND GATE	RESISTANCE		-		-		-
Input Capacitance	C <sub>iss</sub>	V <sub>GS</sub> = 0 V, f = 1.0 MHz, V <sub>DS</sub> = 24 V			1078		pF
Output Capacitance	C <sub>oss</sub>				460		1
Reverse Transfer Capacitance	C <sub>rss</sub>				127		
Total Gate Charge	$Q_{G(TOT)}$				11	18	nC
Threshold Gate Charge	Q <sub>G(TH)</sub>	$V_{GS} = 4.5 \text{ V}, V_{DS} = 15 \text{ V}, I_{D} = 10 \text{ A}$			1.1		1
Gate-to-Source Charge	$Q_{GS}$				2.1		1
Gate-to-Drain Charge	$Q_{GD}$				5.8		1
Gate Resistance	$R_{G}$				1.76		Ω
SWITCHING CHARACTERISTICS (Note	4)		•		•	•	
Turn-On Delay Time	t <sub>d(on)</sub>				7.8		ns
Rise Time	t <sub>r</sub>	Vcs = 10 V. Vpp = 15	V. In = 1.0 A.		4.7		1
Turn-Off Delay Time	t <sub>d(off)</sub>	$V_{GS} = 10 \text{ V}, V_{DD} = 15$ $R_{G} = 3.0$	Ω		27		1
Fall Time	t <sub>f</sub>				17		1
DRAIN-SOURCE DIODE CHARACTERI	STICS				•		-1
Forward Diode Voltage	$V_{SD}$	., .,,,	T <sub>J</sub> = 25°C		0.73	1.0	V
	$V_{GS} = 0 \text{ V, } I_{S} = 3.0 \text{ A}$ $T_{J} = 125^{\circ}\text{C}$	T <sub>J</sub> = 125°C		0.51		1	
Reverse Recovery Time	t <sub>RR</sub>	$V_{GS} = 0 \text{ V, } d_{1S}/d_t = 100 \text{ A/}\mu\text{s,}$ $I_S = 3.0 \text{ A}$			38	1	ns
Charge Time	t <sub>a</sub>				17		1
Discharge Time	t <sub>b</sub>				21		1
Reverse Recovery Charge	Q <sub>RR</sub>				30		nC

Pulse Test: Pulse Width ≤ 300 μs, Duty Cycle ≤ 2%.
 Switching characteristics are independent of operating junction temperatures.

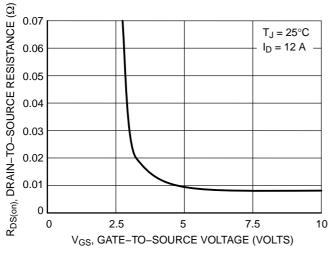
### TYPICAL PERFORMANCE CURVES



 $V_{DS} \ge 10 \text{ V}$   $V_{DS}$ 

Figure 1. On-Region Characteristics

Figure 2. Transfer Characteristics



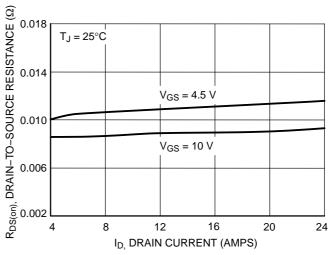
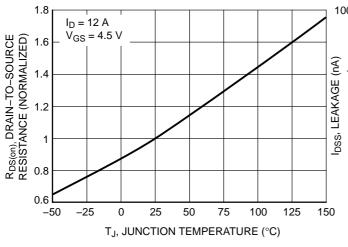


Figure 3. On-Resistance vs. Gate-to-Source Voltage

Figure 4. On–Resistance vs. Drain Current and Gate Voltage



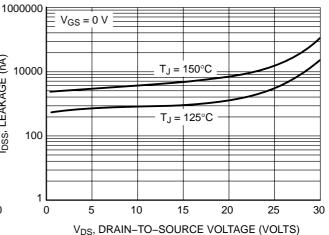
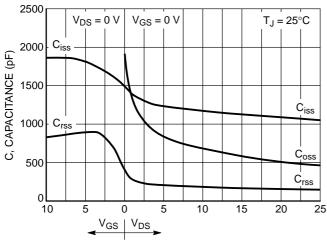


Figure 5. On–Resistance Variation with Temperature

Figure 6. Drain-to-Source Leakage Current vs. Voltage

### TYPICAL PERFORMANCE CURVES



GATE-TO-SOURCE OR DRAIN-TO-SOURCE VOLTAGE (VOLTS)

Figure 7. Capacitance Variation

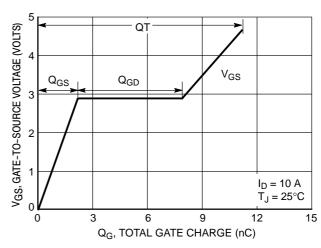


Figure 8. Gate-To-Source and Drain-To-Source Voltage vs. Total Charge

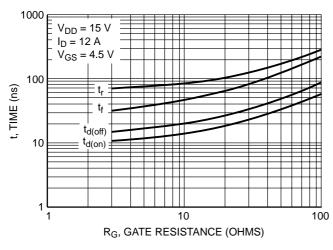


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

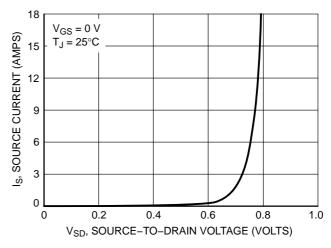


Figure 10. Diode Forward Voltage vs. Current

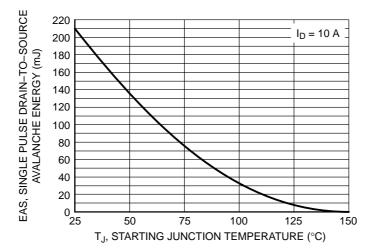
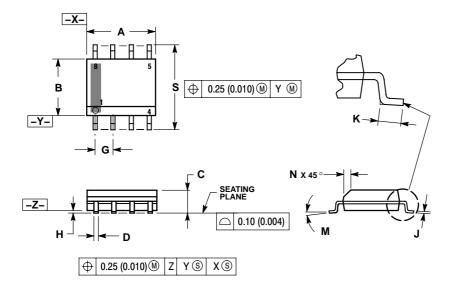


Figure 11. Maximum Avalanche Energy vs.
Starting Junction Temperature

#### PACKAGE DIMENSIONS

### SOIC-8 CASE 751-07 **ISSUE AG**



#### NOTES:

- DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
   CONTROLLING DIMENSION: MILLIMETER.
- DIMENSION A AND B DO NOT INCLUDE MOLD PROTRUSION.
- MAXIMUM MOLD PROTRUSION 0.15 (0.006) PER SIDE.
- PER SIDE.

  5. DIMENSION D DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL BE 0.127 (0.005) TOTAL IN EXCESS OF THE D DIMENSION AT MAXIMUM MATERIAL CONDITION.

  6. 751–01 THRU 751–06 ARE OBSOLETE. NEW STANDARD IS 751–07.

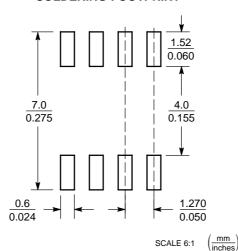
	MILLIMETERS		INC	INCHES		
DIM	MIN	MAX	MIN	MAX		
Α	4.80	5.00	0.189	0.197		
В	3.80	4.00	0.150	0.157		
С	1.35	1.75	0.053	0.069		
D	0.33	0.51	0.013	0.020		
G	1.27 BSC		0.05	0 BSC		
Н	0.10	0.25	0.004	0.010		
7	0.19	0.25	0.007	0.010		
K	0.40	1.27	0.016	0.050		
М	0 °	8 °	0 °	8 °		
Ν	0.25	0.50	0.010	0.020		
S	5.80	6.20	0.228	0.244		

### STYLE 12:

PIN 1. SOURCE

- SOURCE SOURCE 2.
- GATE DRAIN
- DRAIN
- 5. 6. 7. DRAIN
- DRAIN

## **SOLDERING FOOTPRINT\***



\*For additional information on our Pb–Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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